Amendments to the Claims:

1-14. (Previously Cancelled)

15. (Currently Amended) A method for testing memory, said method comprising:

testing functional memory;

repairing the functional memory by adding access to redundant elements;

re-testing the functional memory which has been repaired;

after repairing the functional memory by adding access to redundant elements and after

re-testing the functional memory which has been repaired, adding access to additional redundant

memory without using the additional redundant memory to replace functional ~~replacing failed~~

memory, wherein the additional redundant memory is not required for the repair; and

after repairing and re-testing the functional memory and adding access to the additional

redundant memory which has been added which was not required for the repair, testing the

additional redundant memory which has been added which was not required for the repair.

16. (Previously Presented) A method as recited in claim 15, further comprising using repair

information to repair the memory.

17. (Previously Presented) A method as recited in claim 15, wherein the step of adding access

to additional redundant memory which is not required for the repair comprises forcing usage of

redundant elements which are not needed to be used for repairing the memory.

18. (Previously Presented) A method as recited in claim 15, wherein the step of adding access to additional redundant memory which is not required for the repair comprises faking defects to remap good elements with redundant elements.

19. (Previously Presented) A method as recited in claim 15, further comprising checking interaction between redundant elements of the memory which are not used and adjacent functional memory.

20. (Previously Presented) A method as recited in claim 15, further comprising forcing usage of all redundant elements, and determining whether a detected failure is associated with redundant elements.

21. (Currently Amended) A mode for testing memory, said mode comprising:

means for testing functional memory;

repairing the functional memory by adding access to redundant elements;

means for re-testing the functional memory which has been repaired;

means for, after repairing the functional memory by adding access to redundant elements and after re-testing the functional memory which has been repaired, adding access to additional redundant memory without using the additional redundant memory to replace functional replacing failed memory, wherein the additional redundant memory is not required for the repair; and

means for, after repairing and re-testing the functional memory and adding access to the additional redundant memory which has been added which was not required for the repair, testing the additional redundant memory which has been added which was not required for the repair.

22.   (Previously Presented) A mode as recited in claim 21, further comprising means for using repair information to repair the memory.

23.   (Previously Presented) A mode as recited in claim 21, further comprising means for forcing usage of redundant elements which are not needed to be used for repairing the memory.

24.   (Previously Presented) A mode as recited in claim 21, further comprising means for faking defects to remap good elements with redundant elements.

25.   (Previously Presented) A mode as recited in claim 21, further comprising means for checking interaction between redundant elements of the memory which are not used and adjacent functional memory.

26.   (Previously Presented) A mode as recited in claim 21, further comprising means for forcing usage of all redundant elements, and determining whether a detected failure is associated with redundant elements.